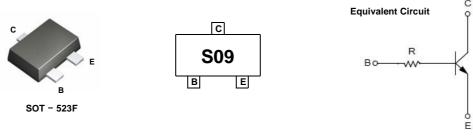


July 2007

FJY3009R NPN Epitaxial Silicon Transistor

Features

- · Switching circuit, Inverter, Interface circuit, Driver Circuit
- Built in bias Resistor (R=4.7KΩ)
- Complement to FJY4009R



Absolute Maximum Ratings * Ta = 25°C unless otherwise noted

Symbol	Parameter	Value	Units
V _{CBO}	Collector-Base Voltage	40	V
V _{CEO}	Collector-Emitter Voltage	40	V
V _{EBO}	Emitter-Base Voltage	5	V
I _C	Collector Current	100	mA
T _{STG}	Storage Temperature Range	-55~150	°C
T _J	Junction Temperature	150	°C
P _C	Collector Power Dissipation, by $R_{\theta JA}$	200	mW

^{*} These ratings are limiting values above which the serviceability of any semiconductor device may by impaired.

Thermal Characteristics* Ta=25°C unless otherwise noted

Symbol	Parameter	Max	Units	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	600	°C/W	
* Minimum land pad size.				

Electrical Characteristics* $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Condition	MIN	Тур	MAX	Units
V _(BR) CBO	Collector-Emitter Breakdown Voltage	Ic = 100 uA, IE = 0	40			V
V _(BR) CEO	Collector-Base Breakdown Voltage	Ic = 1mA, IB = 0	40			V
Ісво	Collector-Cutoff Current	Vcb = 30 V, IE = 0			0.1	uA
hfE	DC Current Gain	VcE = 5 V, Ic = 1 mA	100		600	
V _{CE} (sat)	Collector-Emitter Saturation Voltage	Ic = 10 mA, I _B = 1 mA			0.3	V
fτ	Current Gain - Bandwidth Product	VcE = 10V, Ic = 5 mA		250		MHz
Ccb	Output Capacitance	Vcb = 10 V, IE = 0, f = 1.0 MHz		3.7		pF
R	Input Resistor		3.2	4.7	6.2	ΚΩ

^{*} Pulse Test: PW≤300μs, Duty Cycle≤2%

Typical Performance Characteristics

Figure 1. DC current Gain

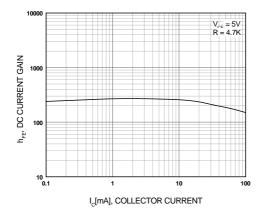


Figure 2. Collector-Emitter Saturation Voltage

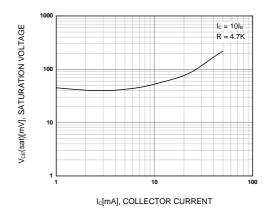
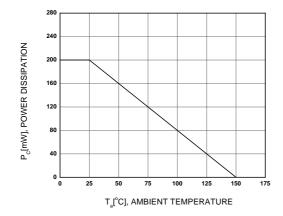
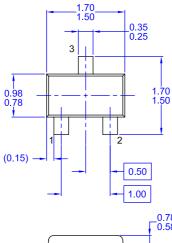


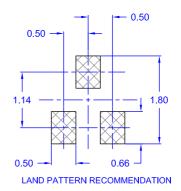
Figure 3. Power Derating

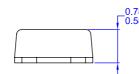


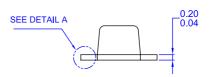
Package Dimensions

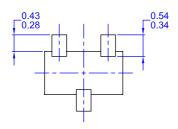
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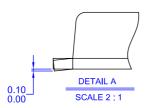












- NOTES: UNLESS OTHERWISE SPECIFIED A) THIS PACKAGE CONFORMS TO EIAJ SC89 PACKAGING STANDARD.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
 C) DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.

Dimensions in Millimeters



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